

Notice of References Cited	Application/Control No. 10/043,637	Applicant(s)/Patent Under Reexamination KHU ET AL.	
	Examiner XUAN M. THAI	Art Unit 2111	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,706,297	01-1998	Jeppesen et al.	714/30
	C	US-5,708,773	01-1998	Jeppesen et al.	714/30
	D	US-6,112,298	08-2000	Deao et al.	712/227
	E	US-6,243,842	06-2001	Slezak et al.	714/724
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NON-PATENT DOCUMENTS

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	U	Narayanan et al., "Reconfigurable Scan Chains: A Novel Approach to Reduce Test Application Time", IEEE, 1993, pages 710-715.
	V	Robinson, Gordon D. "Why 1149.1 (JTAG) Really Works", Electro/94 International. Conference Proceedings Combined Volumes, 10-12 May 1994, pages 749-754.
	W	"Boundary Scan Descriptive Language for Non-JTAG Components" IBMTDB, October 1993, vol. 36, issue no. 10, pages 599-600.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.